

The VLSI/ASIC based readout technology for the spectroscopic signal processing of the UHV compatible Si multi detector system (CHICSi).

Pavel Golubev and the CHIC* collaboration

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- Uppsala University, TSL, Sweden
- University of Jyväskylä, Finland
- SINTEF Electronics and Cybernetics, Oslo, Norway

* CELSIUS Heavy Ion Collaboration



Outlook

- *The CHICSi detector*
- *Front-End Readout Electronics CHICSi ASIC chip (Mk.2)*
- *ASIC card in UHV*
- *Practical experience*
- *PICA Project (Pulse Instrumentation Chip for analytical Applications)*
- *Summary and outlook*

“CHICSi – a compact ultra–high vacuum compatible detector system for nuclear reaction experiments at storage rings”.

I. General structure, mechanics and UHV compatibility.

NIM A 500 (2003) 84

II. Detectors.

NIM A 500 (2003) 96

III. Readout system.

NIM A 516 (2004) 327

The CHICSi detector



• CHICSi -program

- Modular
- UHV compatible
- 3π covering
- Cluster-jet target

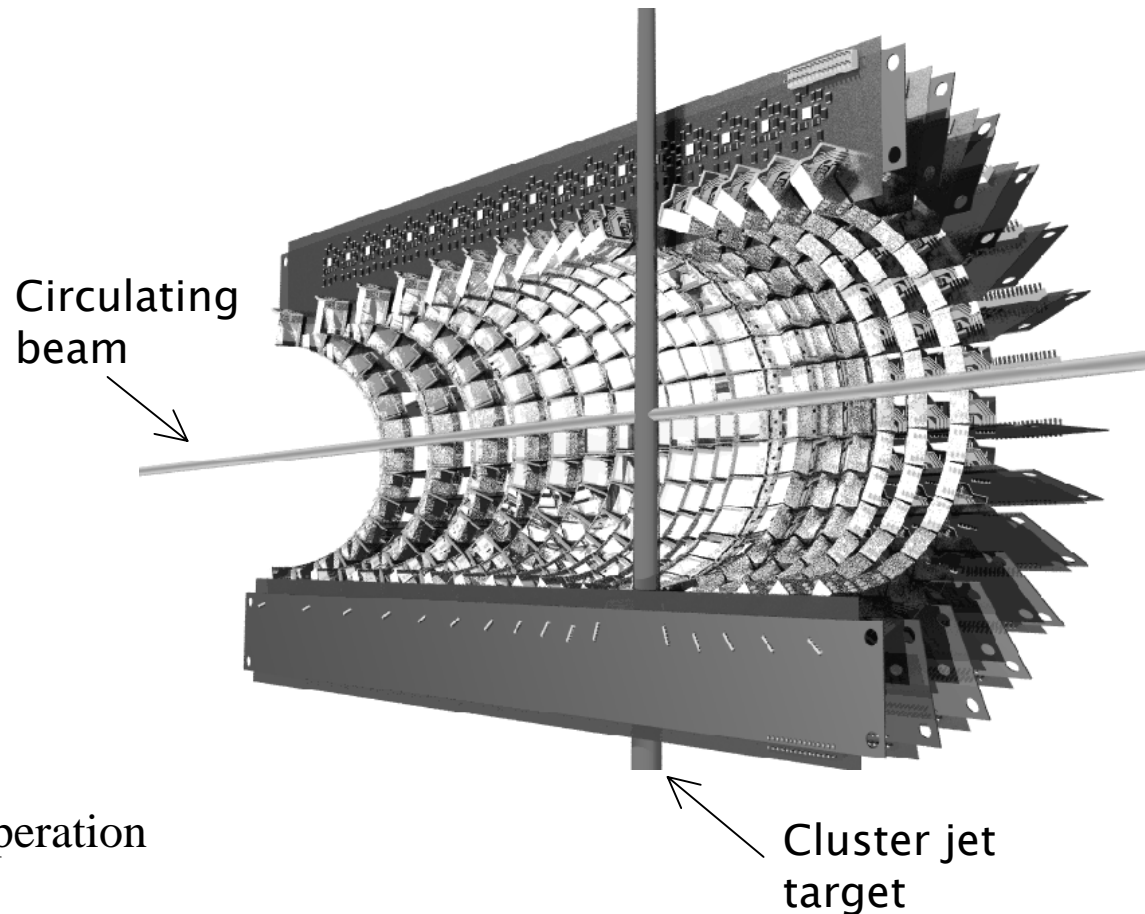
• Missions

- IMF
- Event characterizing device
- Event-by-event
- Energy range 0.7 – 60A MeV

• Major challenges:

- Reduce costs
- Compact for in-UHV operation
- High granularity
- Integrate readout of different types of detector

One half of central CHICSi detector



Detector telescope

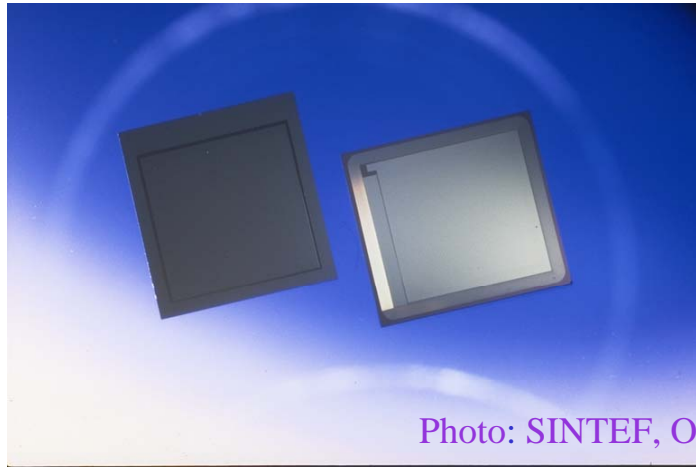
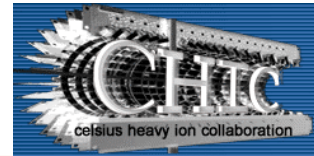
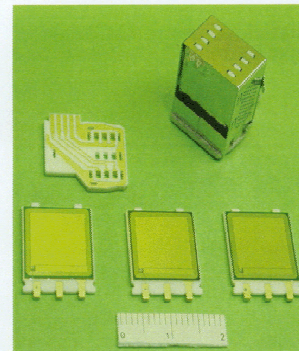
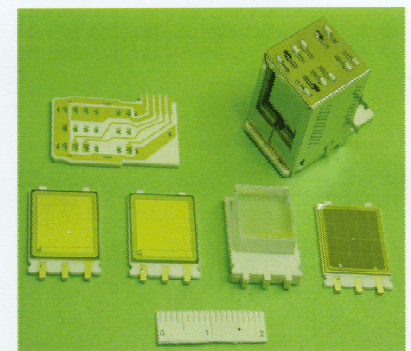


Photo: SINTEF, Oslo

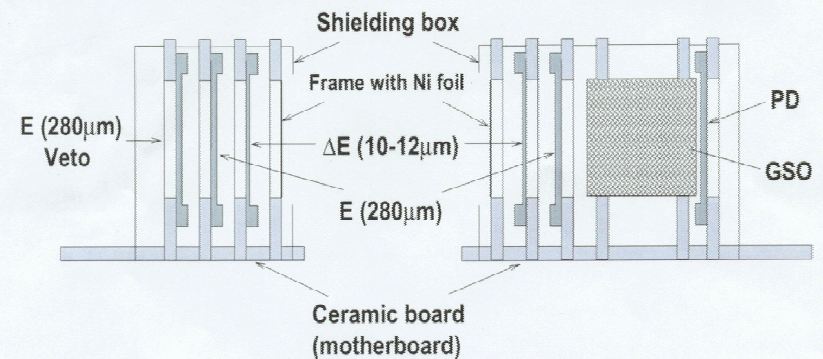
- Construction of CHICSi readout chip with SINTEF Oslo/Austria Mikro System/IMEC
- Industrial production of 10–12 μm Si DE detectors developed with SINTEF Oslo
- Development of detector mounting with Monolitsystem AB Gothenburg
- Multilayer UHV compatible circuit boards and wire bonding FyTech Malmö



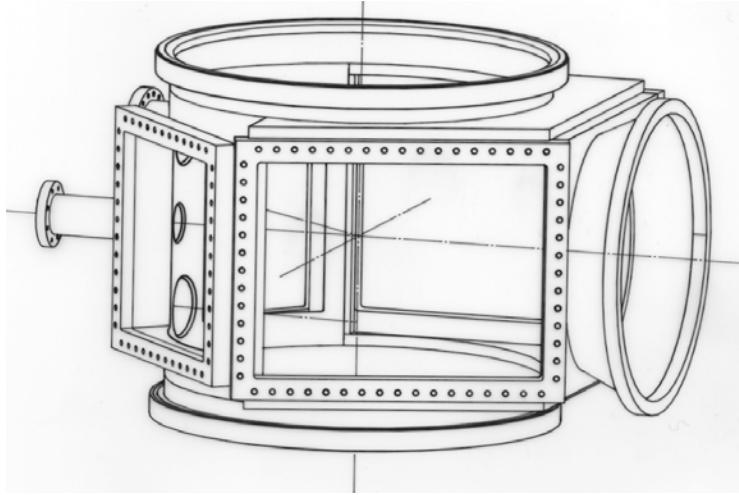
Large Angle Telescope



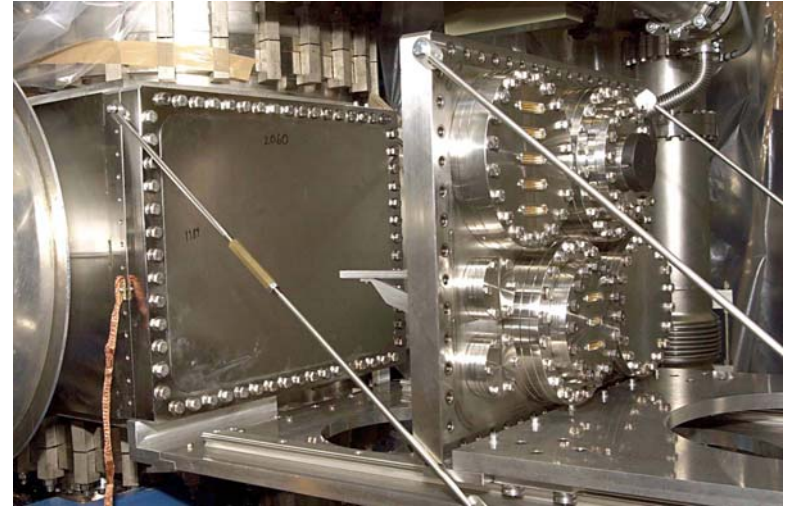
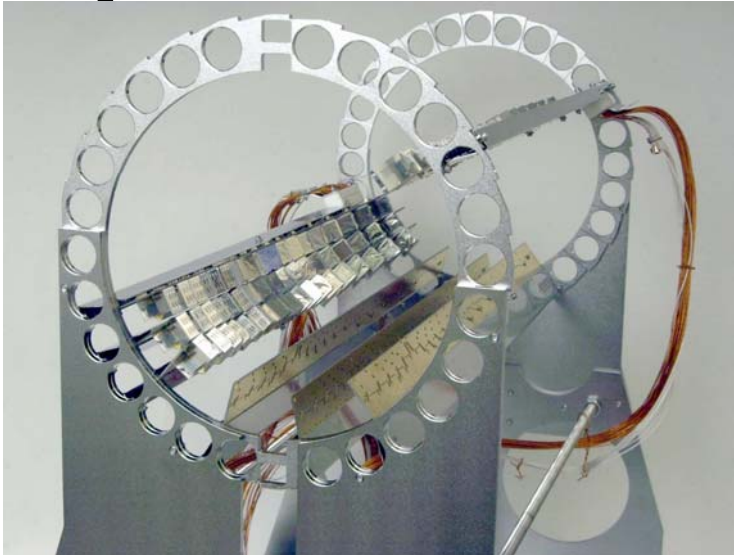
Forward Angle Telescope



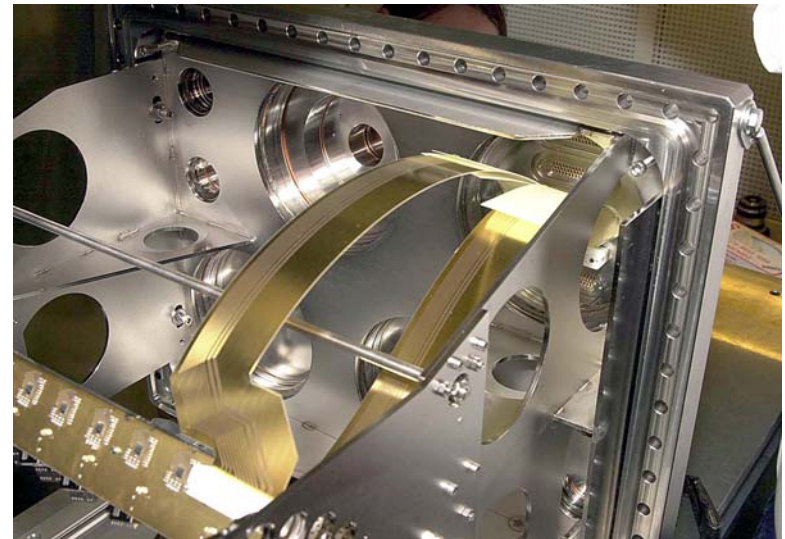
Scattering chamber



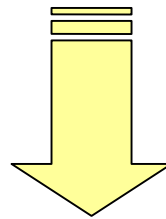
Kapton-insulated cables



Printed-circuit board cable

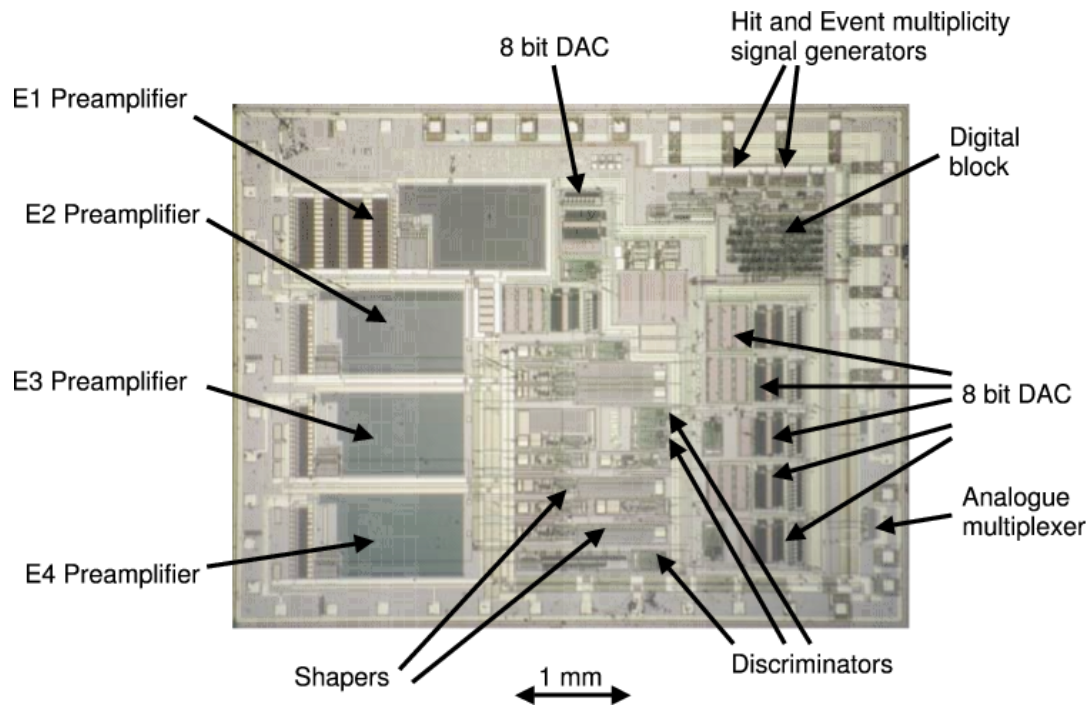
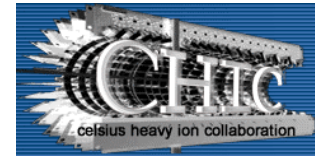


- Read out a large number (~ 2000) detectors
- UHV environment ($\sim 10^{-8}$ Pa)
- Free-running spectroscopy channels
- On-line trigger decision (particle- of IMF's multiplicity)
- Best and most economical readout scheme
- High-quality spectroscopy, wide dynamic range
- Singles event rate $\sim 10^4/\text{sec}$, valid ev. rate \sim few 100/sec
- ...



Readout scheme based on Application Specific Integrated Circuit (ASIC) with Very Large Scale Integration (VLSI)

CHICSi ASIC chip (Mk.2)



- 0.8 μ m high resistive poly2 BiCMOS technology
- Area $5.67 \times 4.370 = 24.78 \text{ mm}^2$
- Power consumption $\sim 45 \text{ mW}$
- Analogue/Digital ASIC
- Power $\pm 2\text{V}$, 4 groups

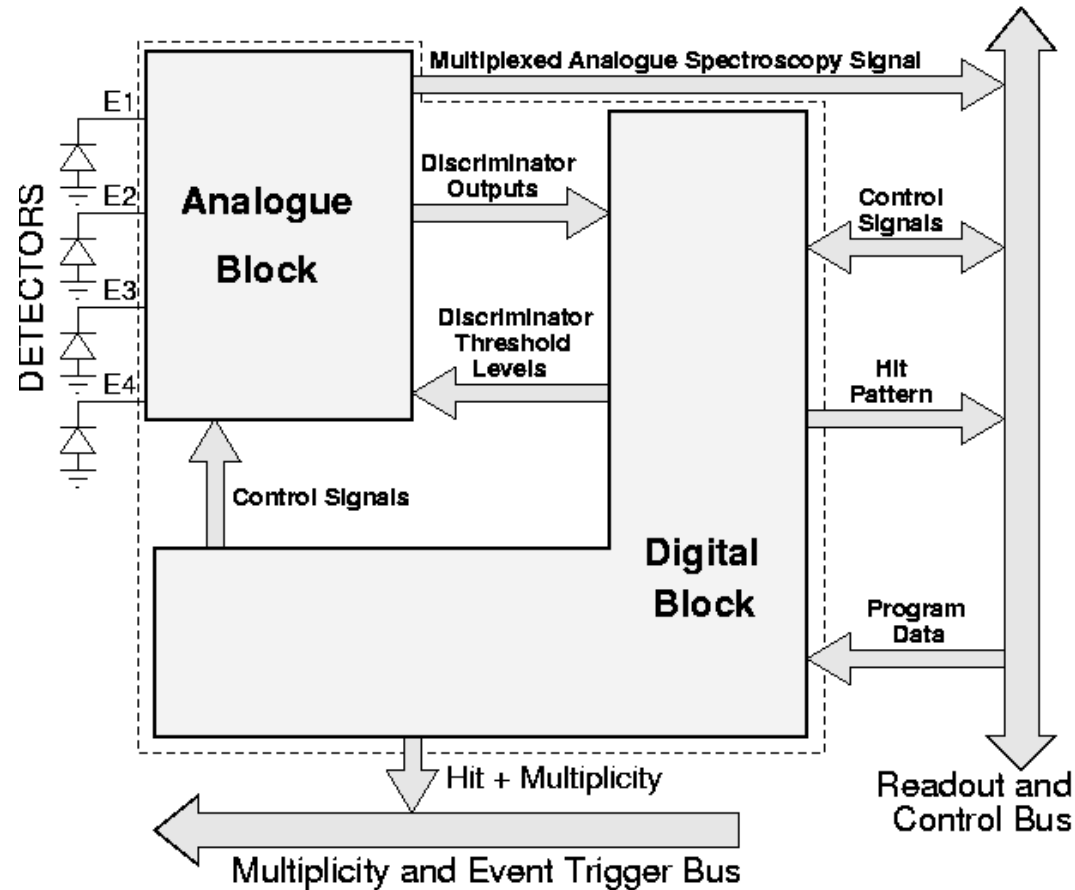
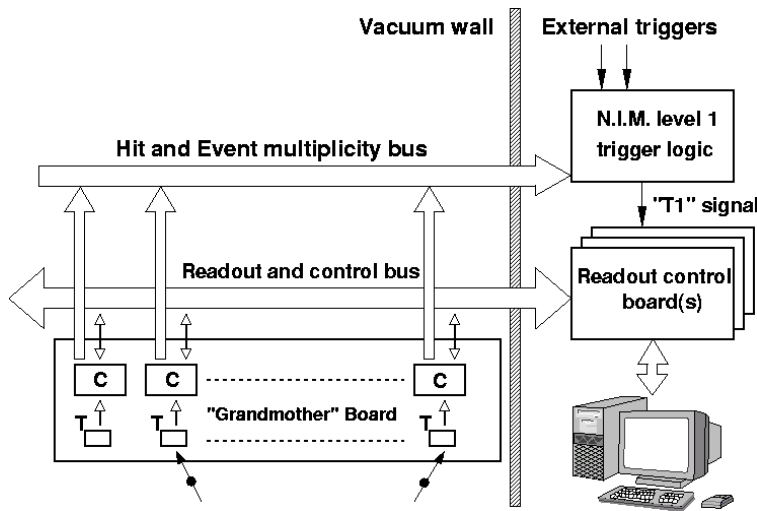
- **Chip technical specification – Detector development group, LU**
- **ASIC design – SINTEF Instrumentation, Oslo**
- **Processed – Austria MicroSysteme International (AMS)**

CHICSi ASIC chip (Mk.2)



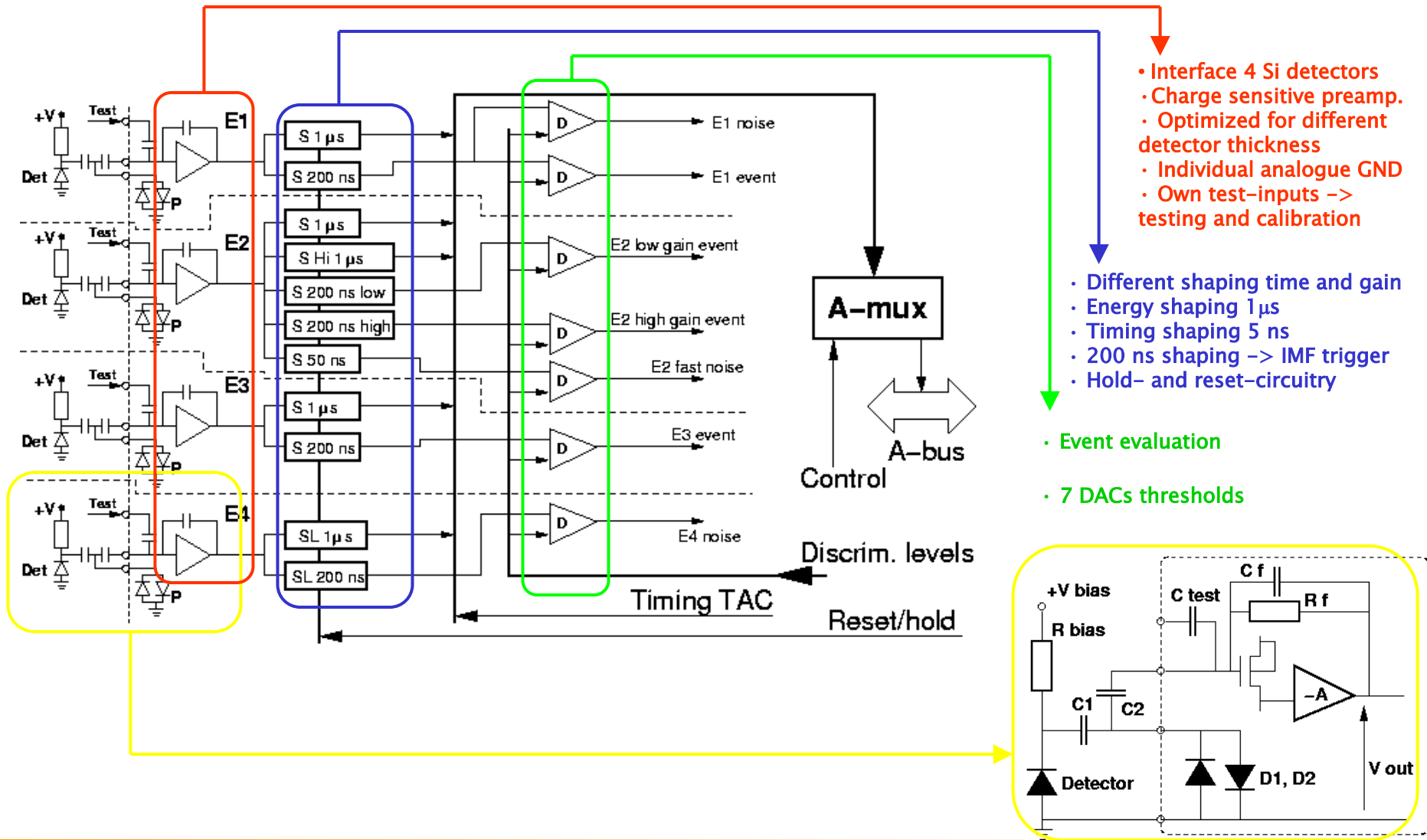
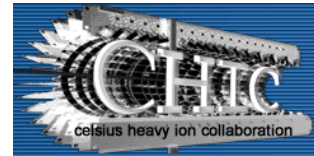
Detector telescope + FEE readout chip:

1. Signal conditioning
2. Analogue memory
3. Trigger signal
4. Interface to serial buses readout



CHICSi ASIC chip (Mk.2)

Analogue block schematic



- Interface 4 Si detectors
- Charge sensitive preamp.
- Optimized for different detector thickness
- Individual analogue GND
- Own test-inputs -> testing and calibration

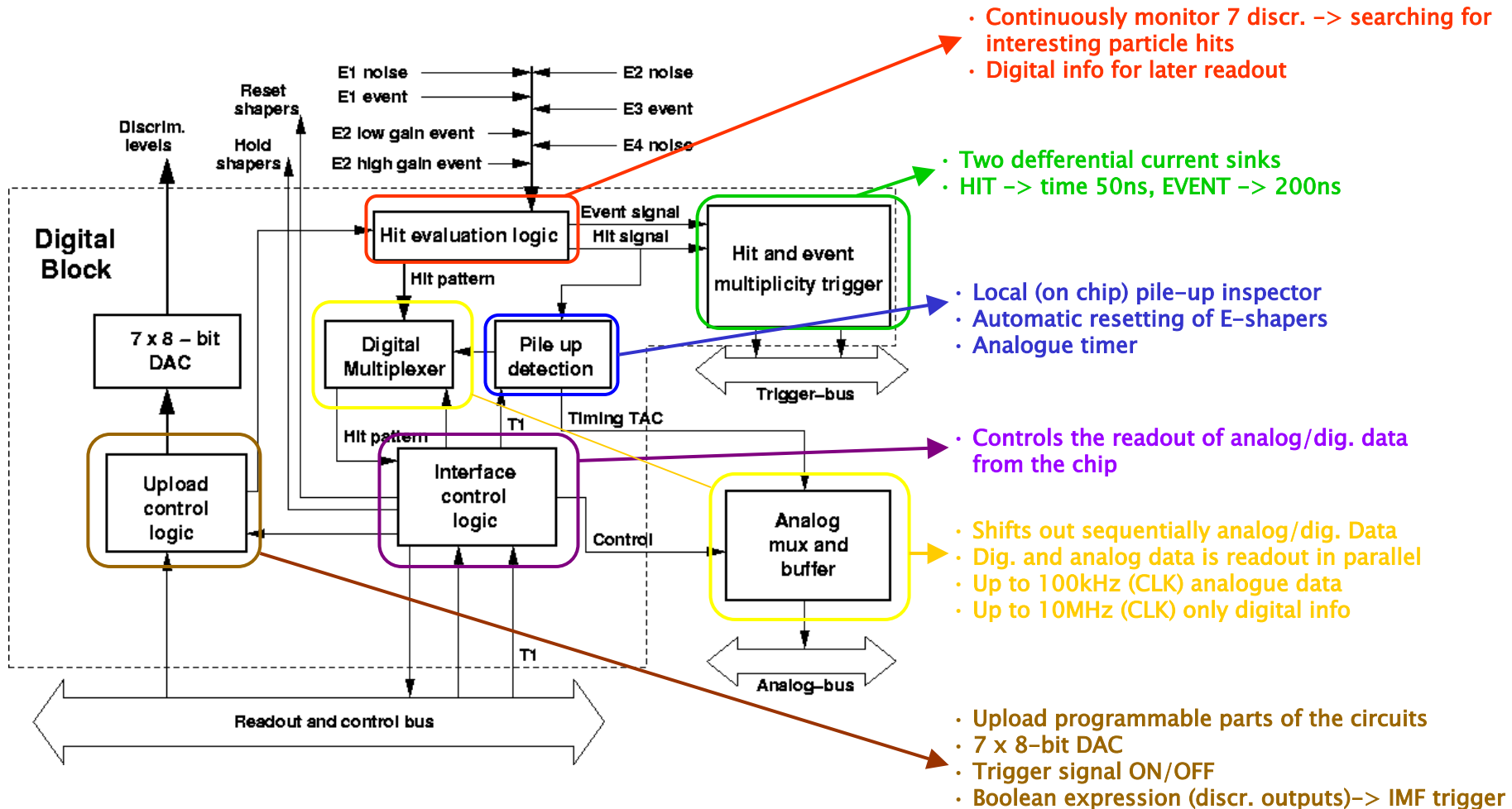
- Different shaping time and gain
- Energy shaping 1 μ s
- Timing shaping 5 ns
- 200 ns shaping -> IMF trigger
- Hold- and reset-circuitry

• Event evaluation

• 7 DACs thresholds

CHICSi ASIC chip (Mk.2)

Digital block schematic



CHICSi ASIC chip (Mk.2)

Typical operations



- **Start up**

Power_Up_Reset, Reset, R_WR, CLK, D_Bus: 58 bits/chip (7 x 8 bit DACs + 2 conf. bits)

- **Trigger → Data readout**

Silent until hit → Level 0 Trigger (HIT, EVENT) → T1 signal from DAQ (1 μ s) → Readout (8 *CLKs*, *Token_in*, ...) analogue/digital info
IF (no data on chip) → zero data suppression (1 *CLK*, *Token_out*)

- **On-line slow control (re-programming)**

- Change DAC settings
- Re-program trigger logic
- ON/OFF chip

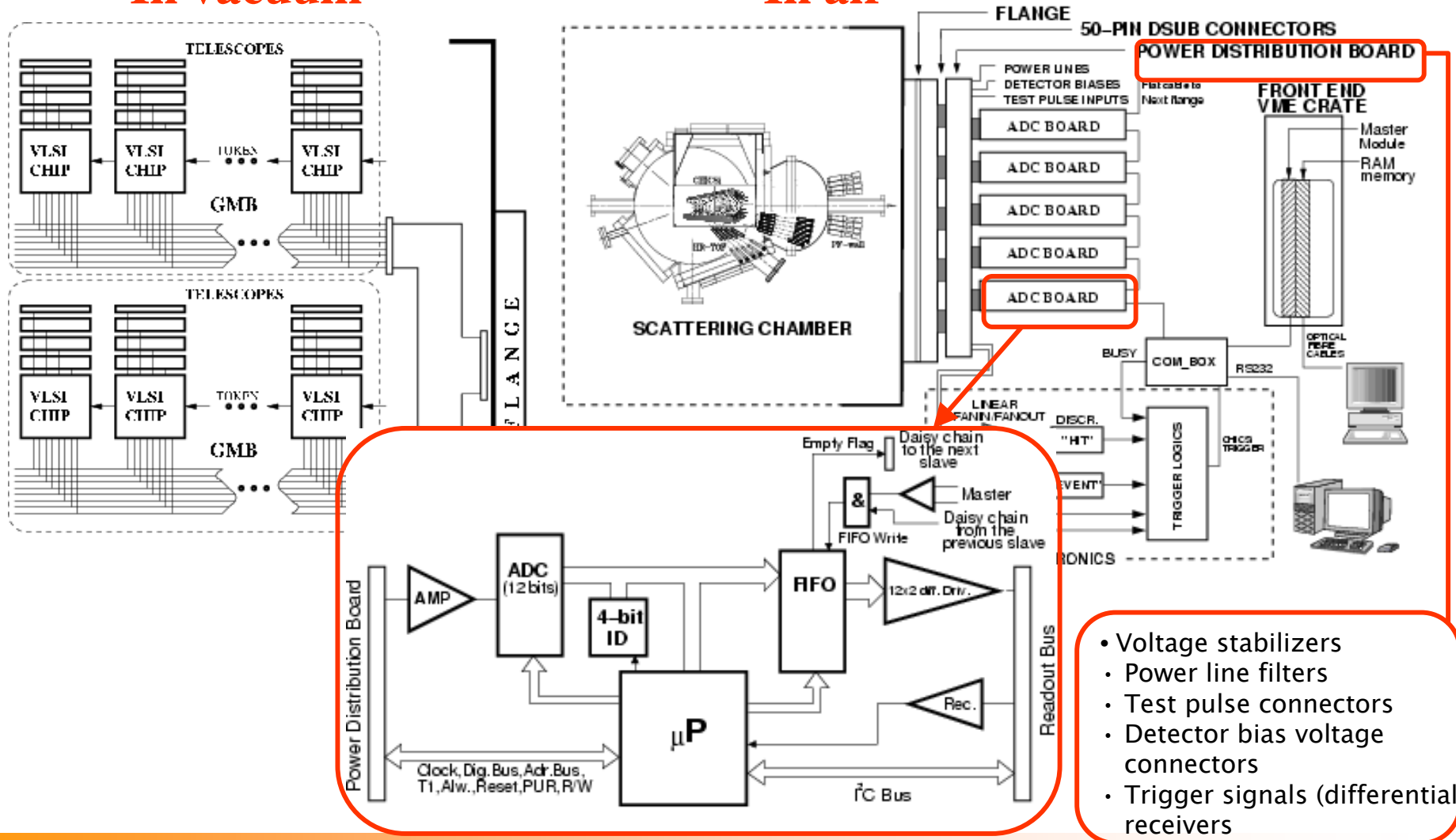
CHICSi ASIC chip (Mk.2)

Data Acquisition System



• In vacuum

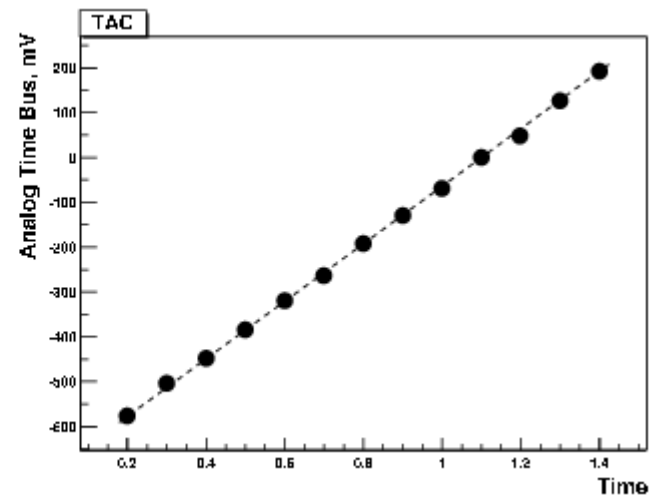
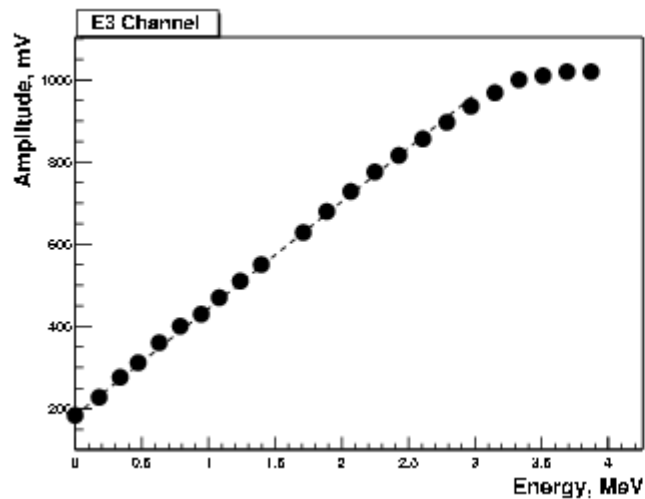
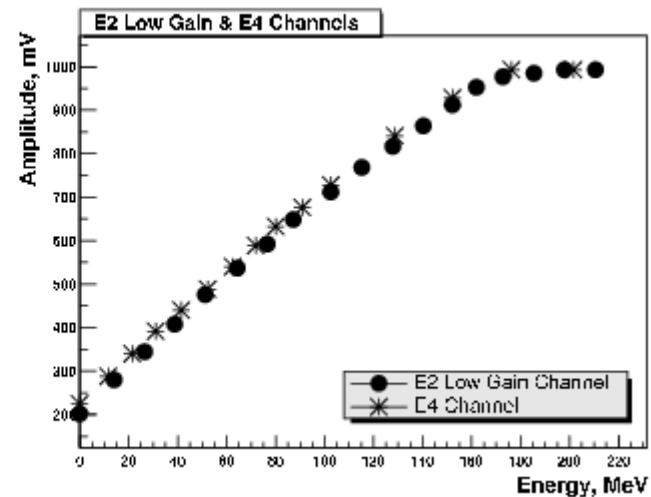
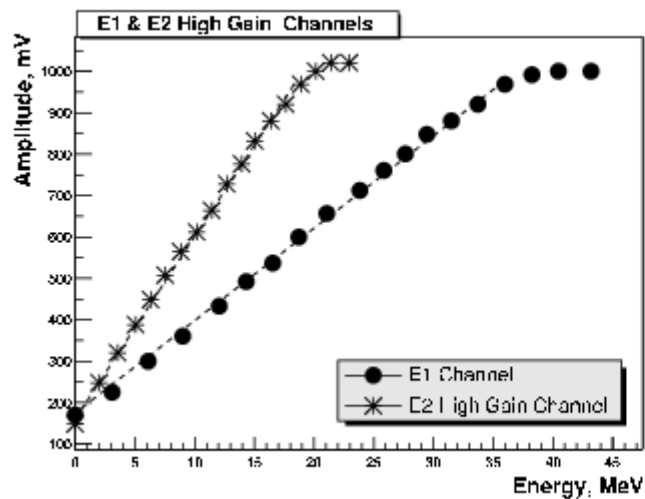
• In air



- Voltage stabilizers
- Power line filters
- Test pulse connectors
- Detector bias voltage connectors
- Trigger signals (differential receivers)

CHICSi ASIC chip (Mk.2)

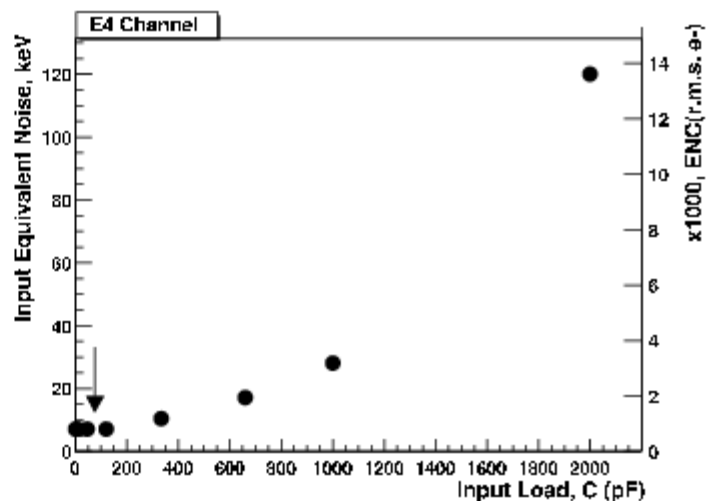
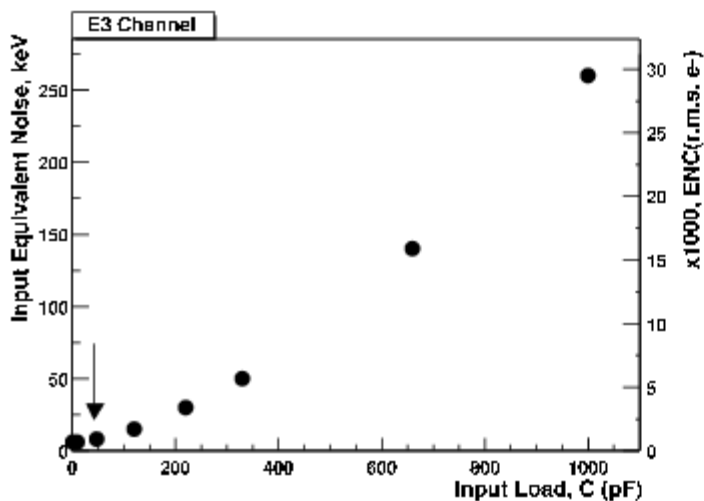
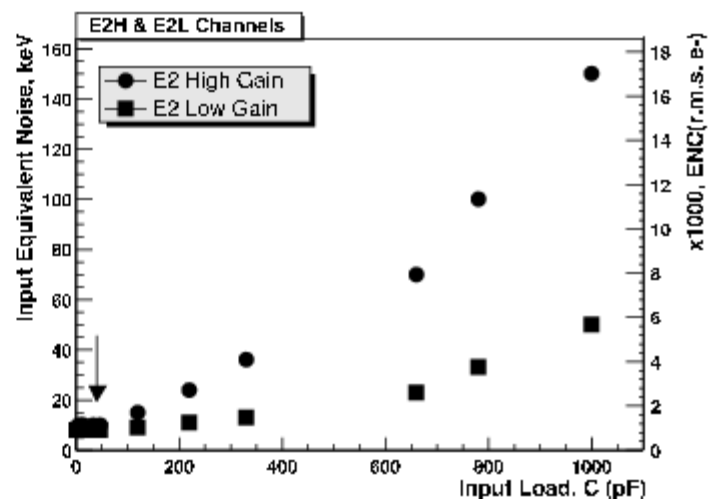
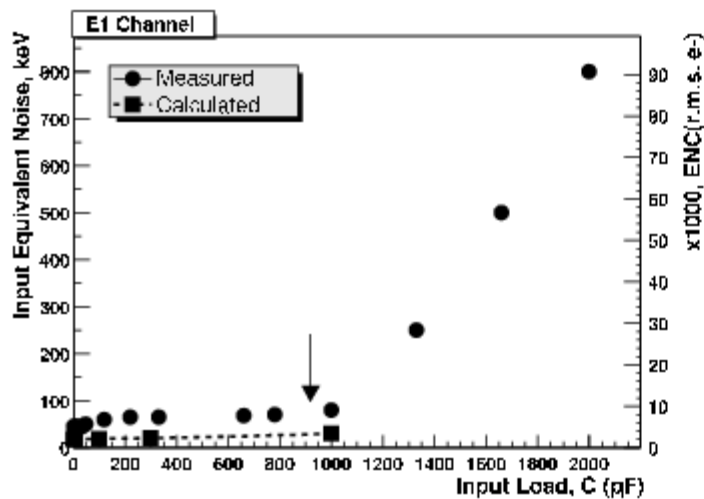
Chip performance



HIT \rightarrow T1, μ s

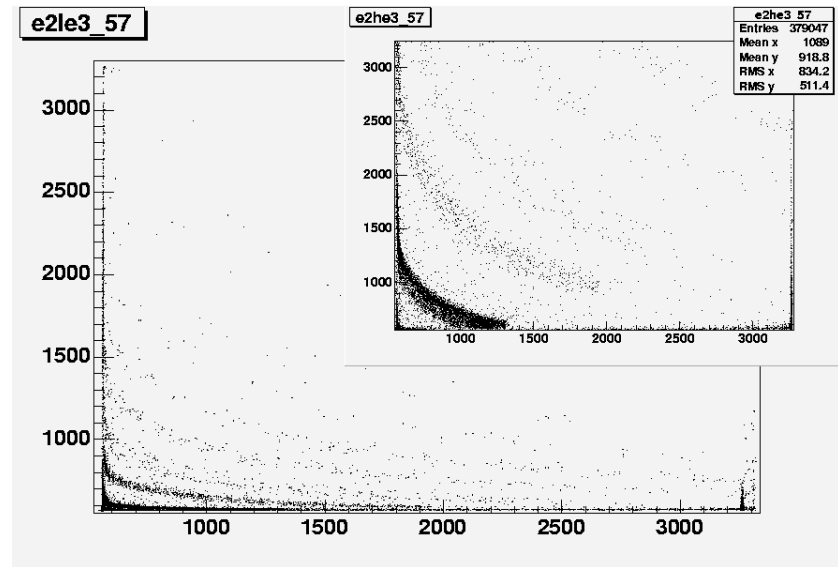
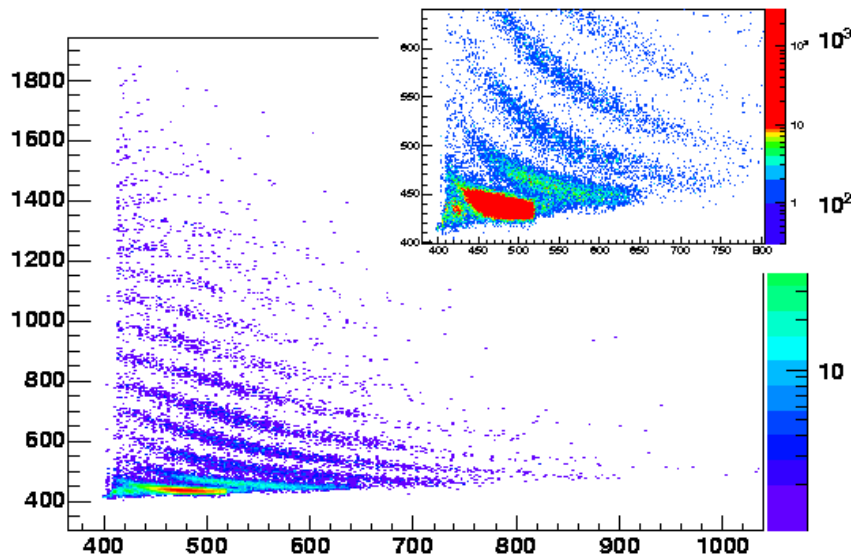
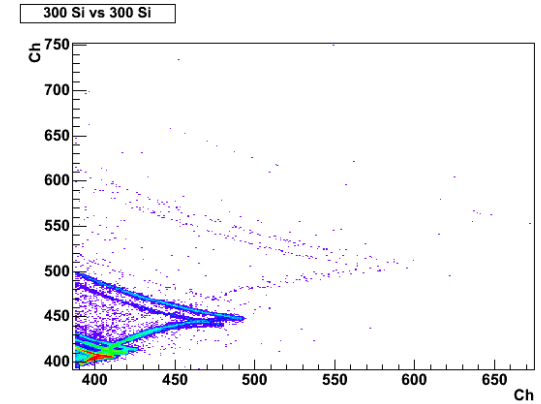
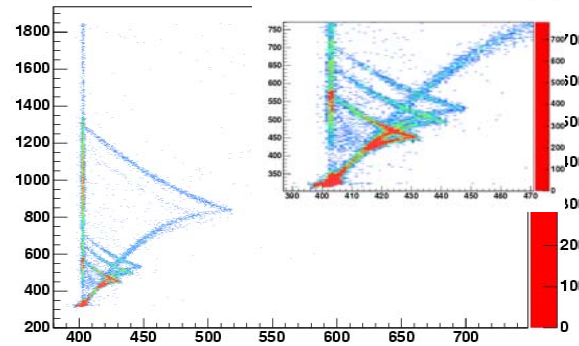
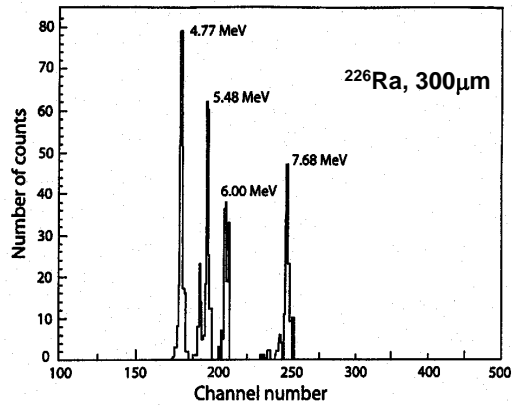
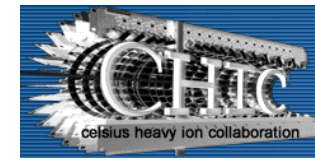
CHICSi ASIC chip (Mk.2)

Chip performance

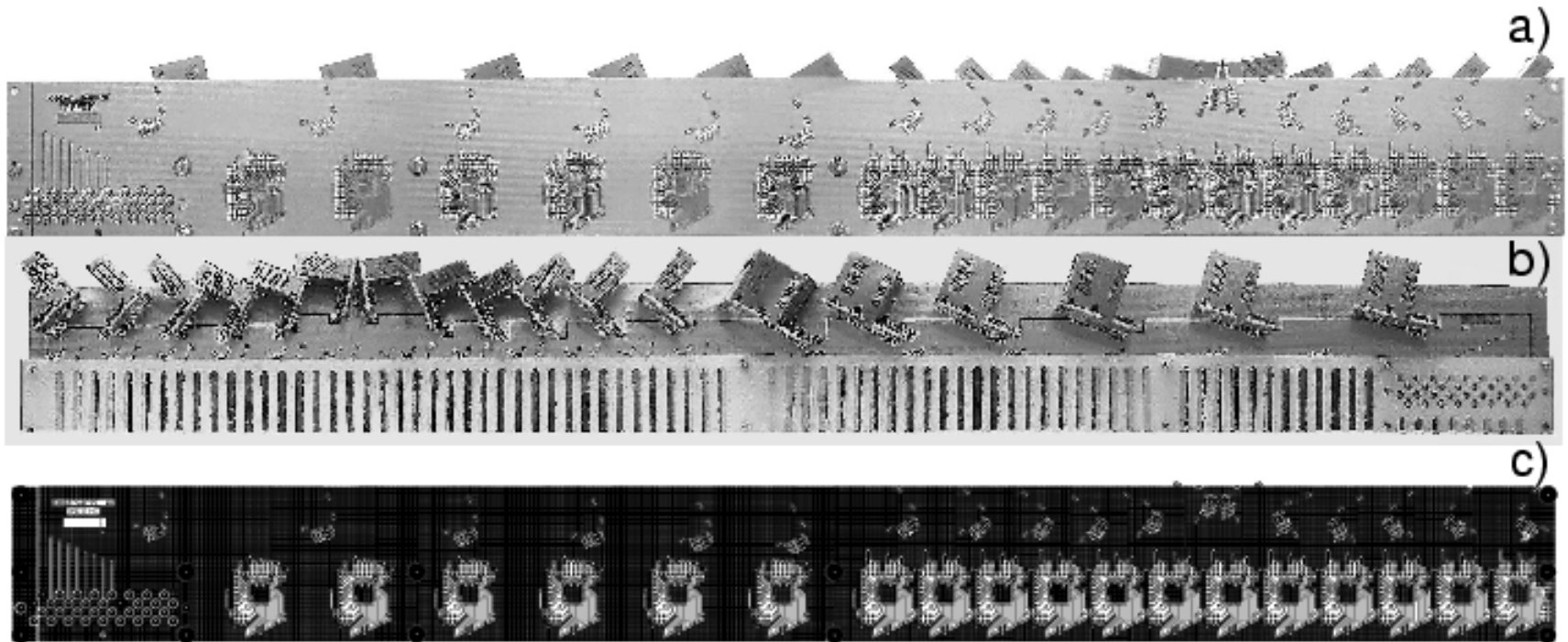
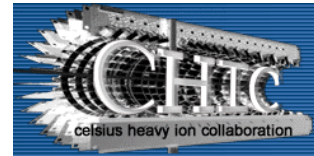


CHICSi ASIC chip (Mk.2)

Chip performance



ASIC card in UHV



- Area 450×45 mm
- Detector telescopes, integrated FEE, connectors, ext. components

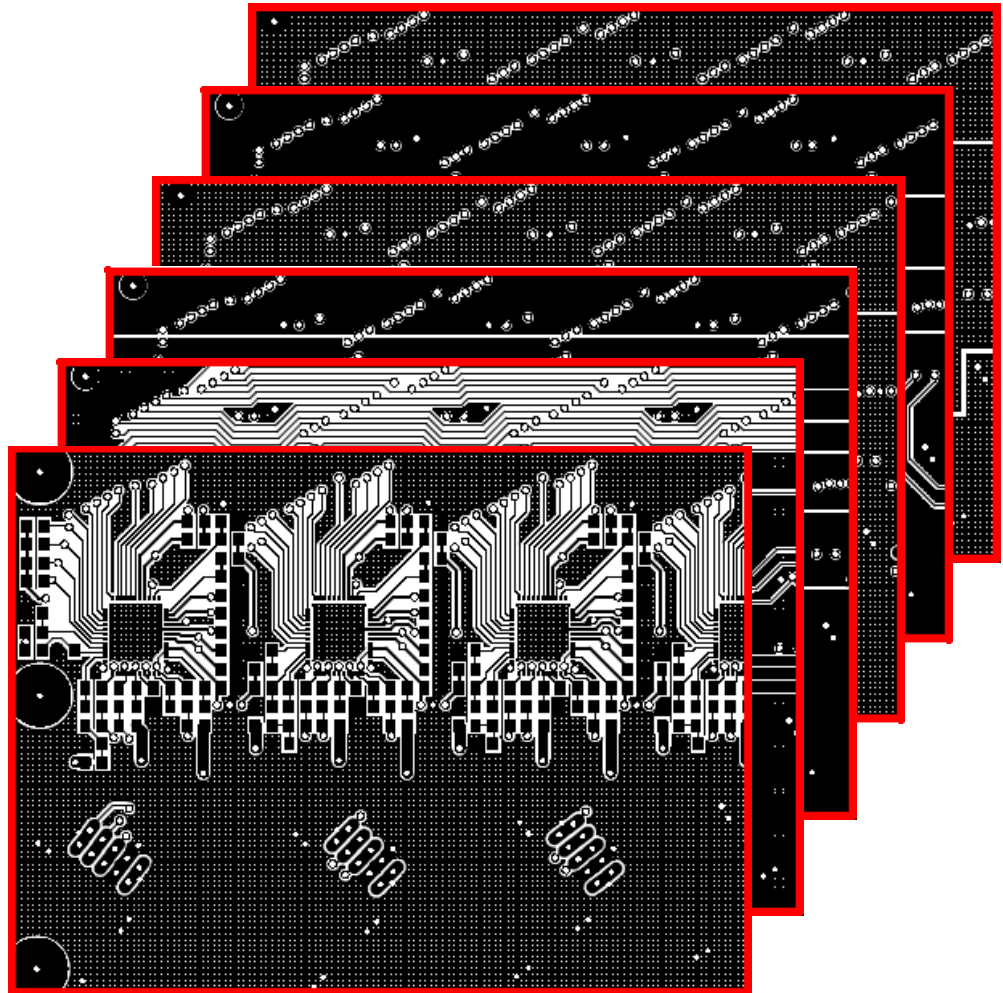
- FR-4, EPO-TEX H20E
- Chip-on-board
- Multi-layer (6 layers) design

ASIC card in UHV

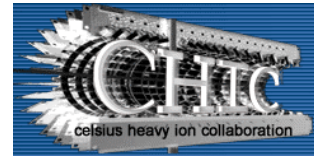
- Large GMB dimensions + long signal/power lines → pickup, cross talk
- 4 groups power lines
- Test lines
- Detector power lines
- Differential trigger signalling
- Private earth line for each detector
- Earth planes on circuit board
- Differential trigger signalling

- Chip-on-board techniques
→ next step:
 - chip-in-cavity
 - flip-chip bonding

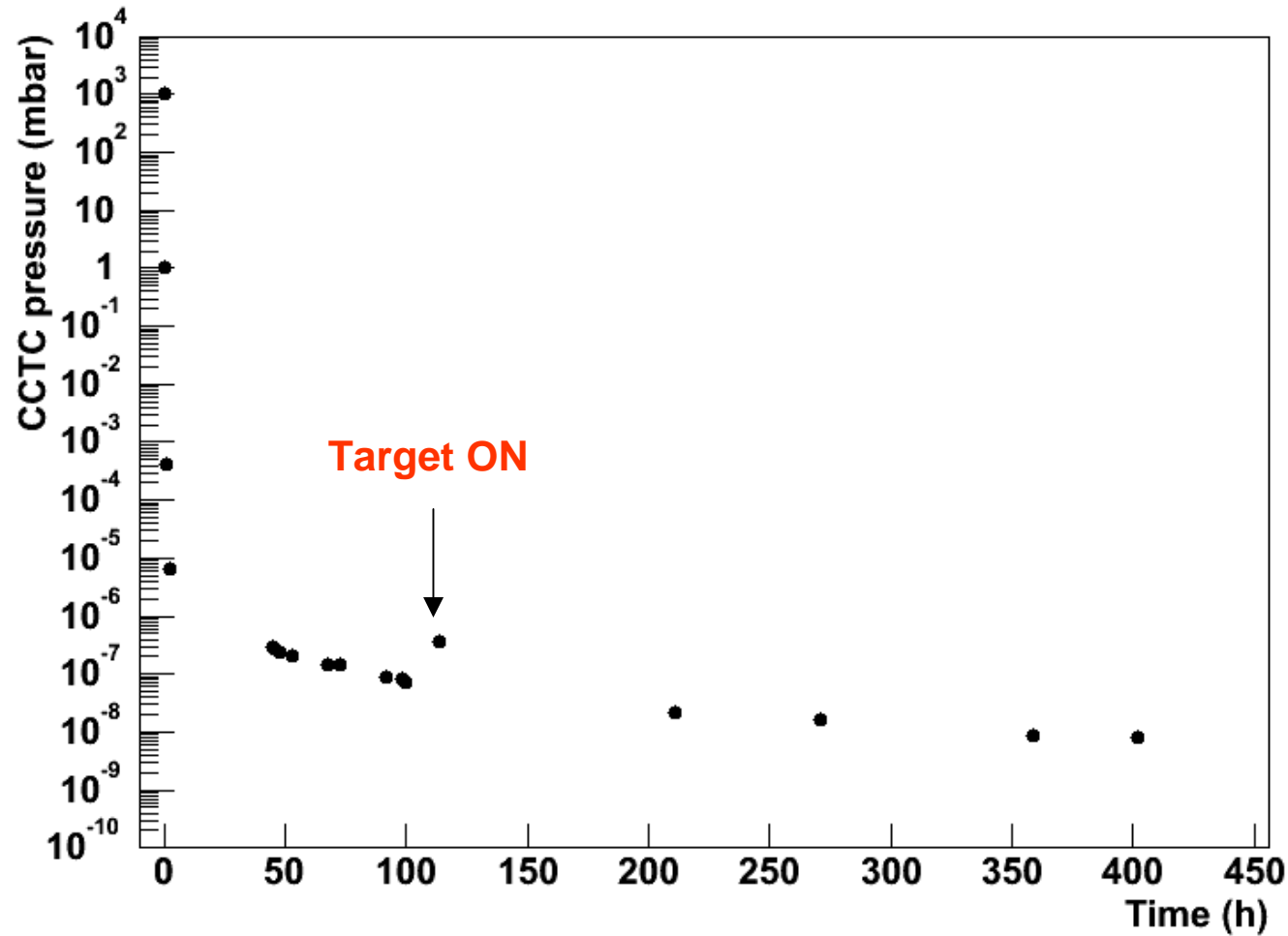
- Simulations



ASIC card in UHV



Target chamber pressure vs. time after installation



Process variations

- Channel to channel
- Chip-to chip
- Wafer to wafer

Intrinsic non-linearity

Amplitude-peaking time
dependence

Dynamic calibration

- Programmable DAC test pulse generator
- Generate global calibration data-base that relates signal in channel to real units

Differential signalling

- Trigger signals
- Spectroscopic signals

Programming

- Chip ON/OFF
- Test inputs ON/OFF
- On-chip trigger logic

External components

- RC chip (biasing resistors)
- Integrate ext. elements

Noise reduction & on-chip cross-talk

- Chip design and process
- Bonding
- Simulations

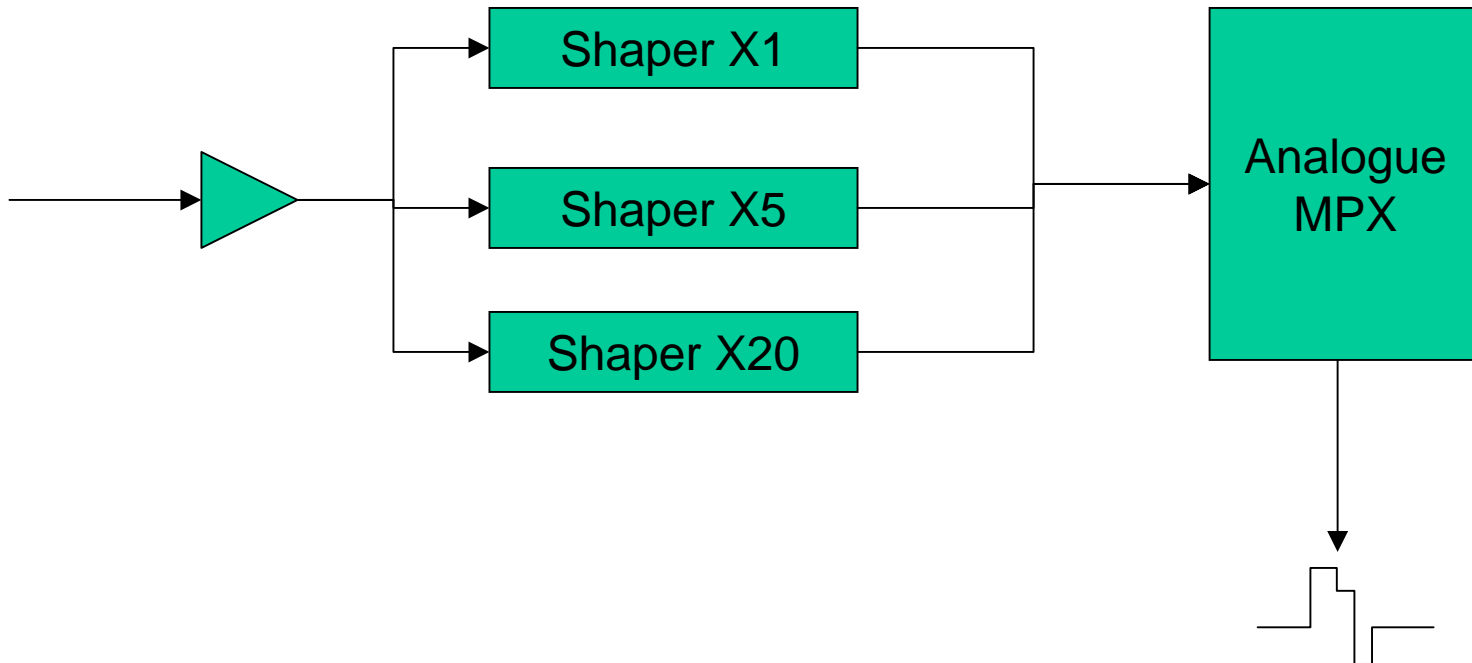
Standard interface

- Single wire
- Wireless (except power lines)
- USB 2.0 is standard (supports buses up to 32 bits wide)
- Easy to find standardized controller and transceivers chips for USB 2.0
- Advantage in UHV

Standard	Bandwidth	Type
USB 1.1	12 Mbps	Wire connection
→ USB 2.0	480 Mbps	Wire connection
→ WLAN 802.11a	54 Mbps	Wireless
WLAN 802.11b	11 Mbps	Wireless
Firewire	800 Mbps	Wire connection
Bluetooth	1 Mbps	Wireless

Implementation of different gains

- **Golden rule** – never reject physically important information
- Not easily possible to change gain on chip – complex circuit needed
- Solution: Use standard fixed-gain modules with different gains and read out all signals.

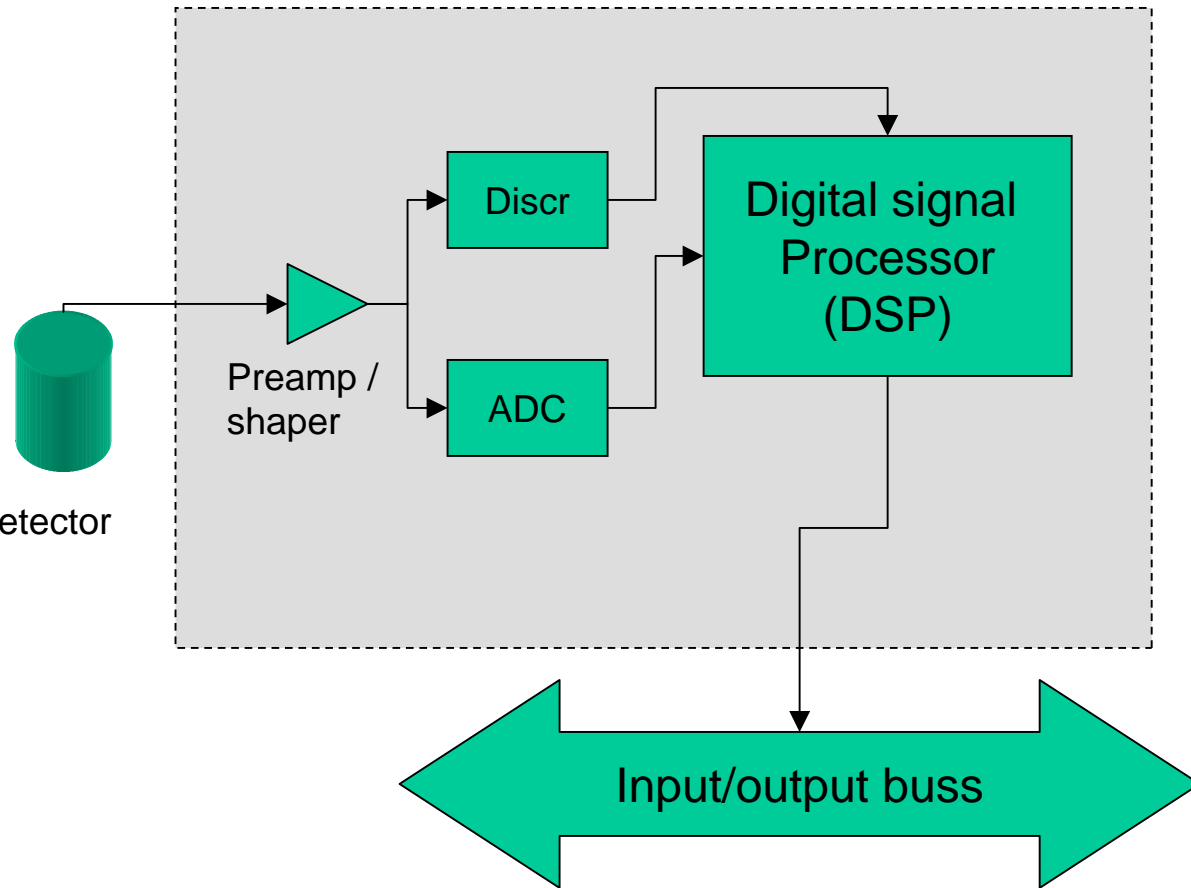


GPS time synchronisation

- GPS – Global Positioning System
- GPS provides global position **and time services**
 - Standard positioning service (SPS) ± 170 ns
 - Precise positioning service (PPS) ± 100 ns
- Common mode time transfer using GPS
 - Time synchronisation within **± 5 ns** over 2 000 km
- GPS time synchronisation could be integrated on the same chip as the readout electronics.

DSP approach

- Idea use high speed digital processor to extract energy, position and time information from each post.
- Possibility to correct for ballistic effects, plasma recombination and also extract *limited* position information
- Useful reduction of chip area as digital electronics is more compact than analogue electronics
- Extreme requirement on sampling ADC
- Noisy fast clock for DSP needed.



Input noise contributions

Flicker

$$ENC = \frac{2.71(C_{det} + C_{in})}{e} \sqrt{\frac{F_k}{2WL}}$$

Channel

$$ENC = \frac{2.71(C_{det} + C_{in})}{e} \sqrt{\frac{\Gamma kT}{3\tau_p g_m}}$$

Bulk

$$ENC = \frac{2.71(C_{det} + C_{in})}{e} \sqrt{\frac{R_{bulk} \eta^2 kT}{2\tau_p}}$$

Bias resistor noise

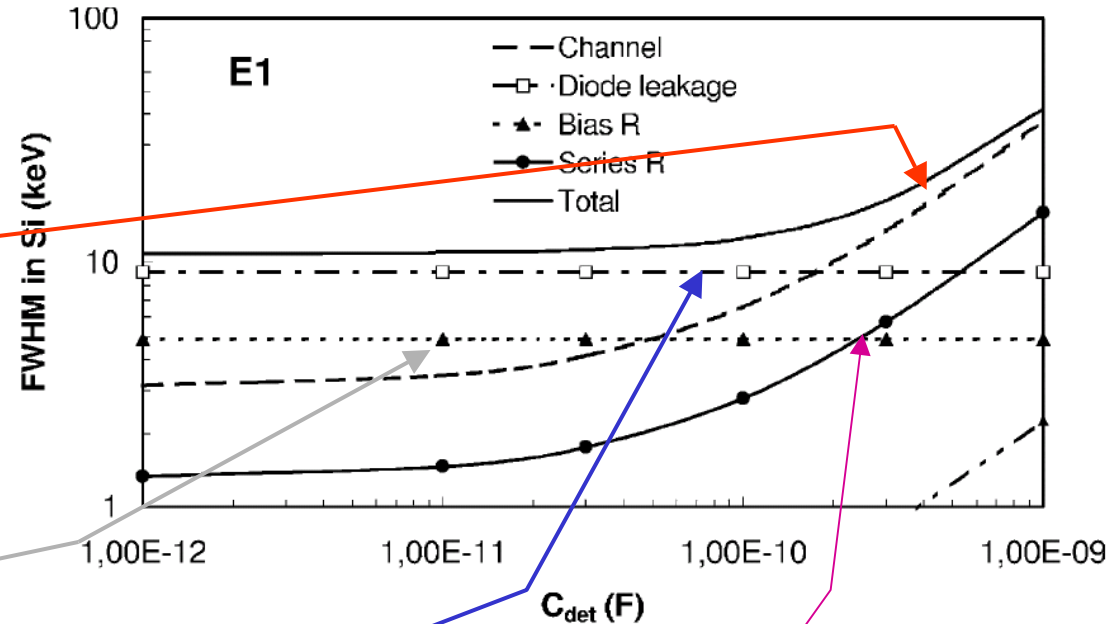
$$ENC = \frac{2.71}{e} \sqrt{\frac{\tau_p kT}{2R_p}}$$

Diode leakage

$$ENC = \frac{2.71}{e} \sqrt{\frac{eI_{det} \tau_p}{4}}$$

Series resistor

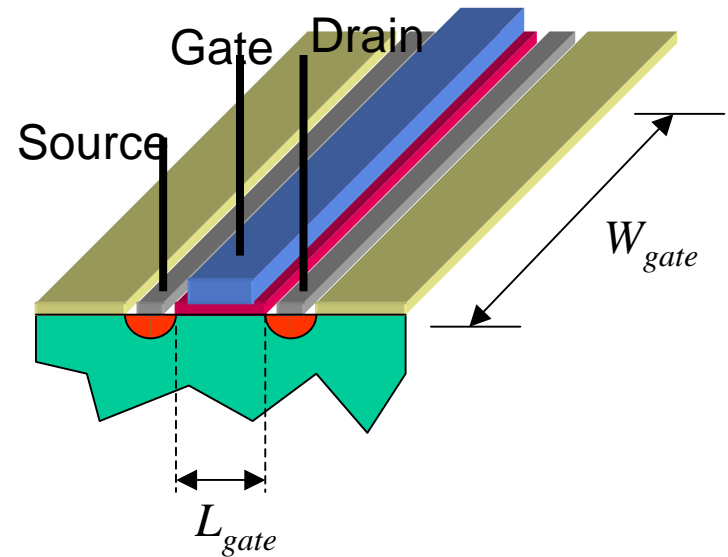
$$ENC = \frac{2.71(C_{det} + C_{in})}{e} \sqrt{\frac{R_{rseries} kT}{2\tau_p}}$$



Process gate width

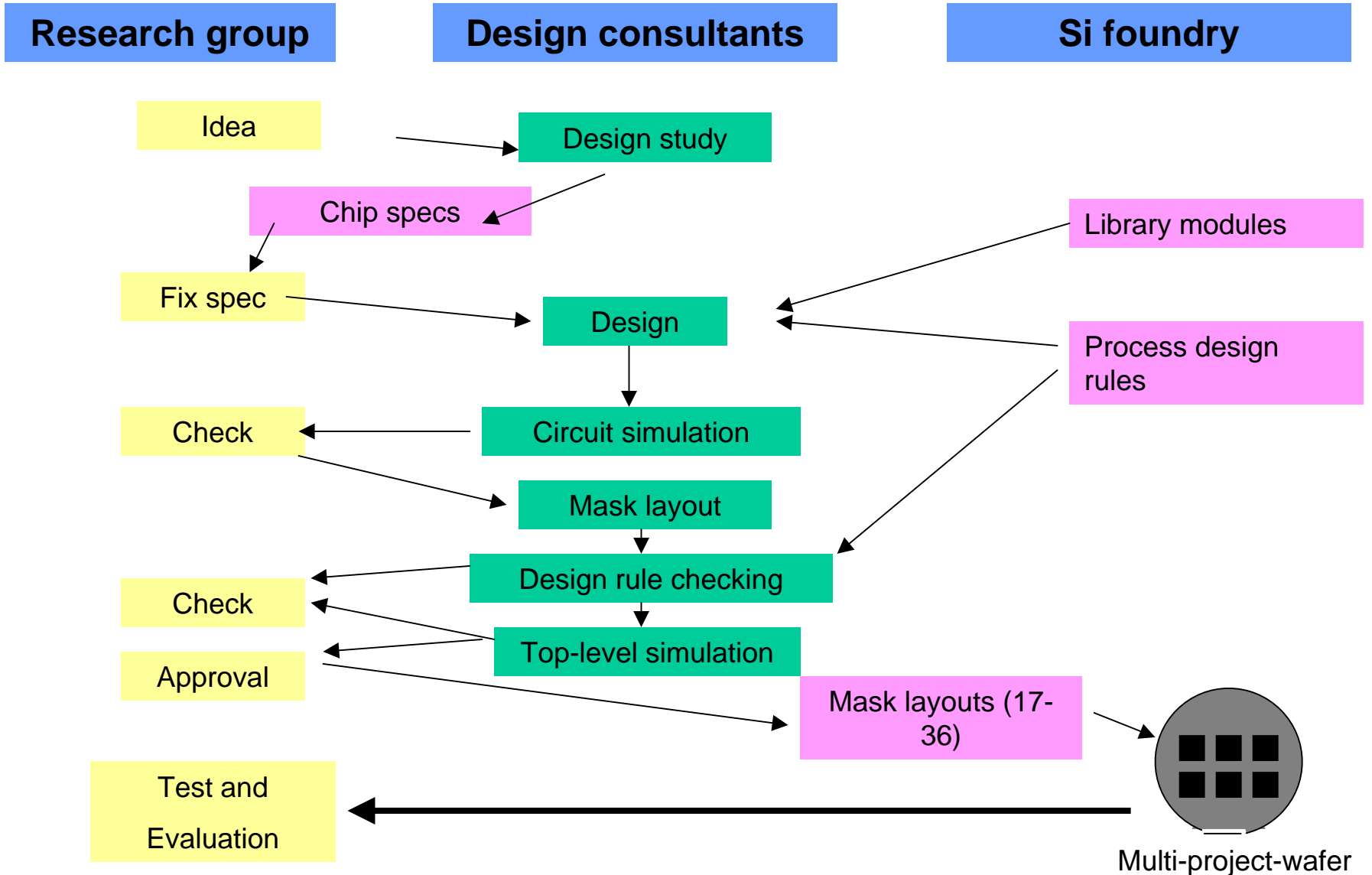
- If both channel length, L , and oxide thickness, t_{ox} , is scaled by $1/\kappa$ and we want to hold on to the criteria $C_{in} = C_{det}/3$
- The transconductance is increased by κ and noise by:

$$\sqrt{\frac{1}{\kappa}}$$



L_{gate}	Relative noise
0.8 μm (CHICSi Mk2 chip)	1
0.18 μm	0.47
90 nm	0.37

ASIC process



PICA

(Pulse Instrumentation Chip for analytical Applications)

Electronic configurations for most forms of pulse spectroscopy measurement are very closely similar →

Solution: integrate electronic readout system (suited for a wide range of physical pulse spectroscopy measurements) into an ASIC chip

- **Standard interface**
 - IEEE 801.b wireless or USB 2.0
 - Low power consumption
 - "Happy measurement" concept
- **Significant user cost reduction**
 - Drastically reduced energy cost
 - Energy cost for 1000 channels NIM: 350 000 SEK/yr: PICA 440 SEK/yr
 - Reduced floorspace
 - Eliminate bulky and expensive cable trunks
 - Mobile and battery operation
 - Remote monitoring
- **No need for expensive software engineering**
 - Simple upgrade
 - Simplified diagnostic
 - Standard software
 - e.g. LabView

Our products

- a. **Standard PICA chip.** This is a flexible readout chip for pulse processing electronics.
- b. **Standard PICA units.** This is a packet solution on a board including standard chip + software + interface. It represents a radical new approach to pulse processing electronics by providing a standard chip that is capable of a wide range of measurements and provides a low-cost *standard* interface to PCs for data collection.
- c. **Development of special chips** for high volume special applications based on adoption of the circuit design modules for the PICA chip to tailor them for special applications.

Summary and outlook (for ASIC design)

- Use a professional design consultant
- Select the process carefully – many are only available for a few years.
- **Never, ever modify a process.** Use a standard process with the function already included.
- Use standard modules for amplifiers, gates, DAC's, ADC's, counters, interface circuits. No need to re-invent the wheel.
- Make complex functions by combining many standard modules
- Include test probe pads where possible – in case things go wrong.
- Assume process variations are large.
- **Simulate.**